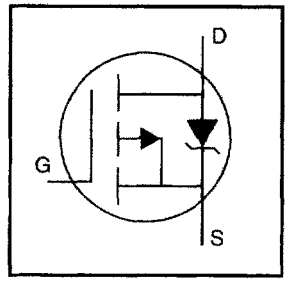
International
IOR Rectifier

PD-9.1484A

IRF9Z24N

HEXFET® Power MOSFET

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated



V_{DSS} = -55V

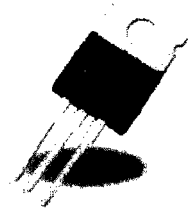
$R_{DS(on)}$ = 0.175Ω

I_D = -12A

Description

Fifth Generation HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design for which HEXFET Power MOSFETs are well known, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



TO-220

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ -10V	-12	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ -10V	-8.5	
I_{DM}	Pulsed Drain Current ①	-48	
P_D @T_C = 25°C	Power Dissipation	45	W
	Linear Derating Factor	0.30	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy ②	96	mJ
I_{AR}	Avalanche Current ①	-7.2	A
E_{AR}	Repetitive Avalanche Energy ①	4.5	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T_J	Operating Junction and	-55 to + 175	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	3.3	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	-55	—	—	V	V_{GS} = 0V, I_D = -250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	-0.05	—	V/°C	Reference to 25°C, I_D = -1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.175	Ω	V_{GS} = -10V, I_D = -7.2A ④
$V_{GS(th)}$	Gate Threshold Voltage	-2.0	—	-4.0	V	V_{DS} = V_{GS}, I_D = -250μA
g_{fs}	Forward Transconductance	2.5	—	—	S	V_{DS} = -25V, I_D = -7.2A
I_{DSS}	Drain-to-Source Leakage Current	—	—	-25	μA	V_{DS} = -55V, V_{GS} = 0V
		—	—	-250		V_{DS} = -44V, V_{GS} = 0V, T_J = 150°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -20V
Q_g	Total Gate Charge	—	—	19	nC	I_D = -7.2A
Q_{gs}	Gate-to-Source Charge	—	—	5.1		V_{DS} = -44V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	10		V_{GS} = -10V, see figure 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	13	—	ns	V_{DD} = -28V
t_r	Rise Time	—	55	—		I_D = -7.2A
$t_{d(off)}$	Turn-Off Delay Time	—	23	—		R_G = 24Ω
t_f	Fall Time	—	37	—		R_D = 3.7Ω, see figure 10 ④
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	350	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	170	—		V_{DS} = -25V
C_{rss}	Reverse Transfer Capacitance	—	92	—		f = 1.0MHz, see figure 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	-12	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	-48		
V_{SD}	Diode Forward Voltage	—	—	-1.6	V	T_J = 25°C, I_S = -7.2A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	47	71	ns	T_J = 25°C, I_F = -7.2A
Q_{rr}	Reverse RecoveryCharge	—	84	130	μC	di/dt = -100A/μs ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (see figure 11)

② Starting T_J = 25°C, L = 3.7mH R_G = 25Ω, I_{AS} = -7.2A (see figure 12)

③ I_{SD} ≤ -7.2A, di/dt ≤ -280A/μs, V_{DD} ≤ $V_{(BR)DSS}$, T_J ≤175°C

④ Pulse width ≤ 300μs; duty cycle ≤ 2%.

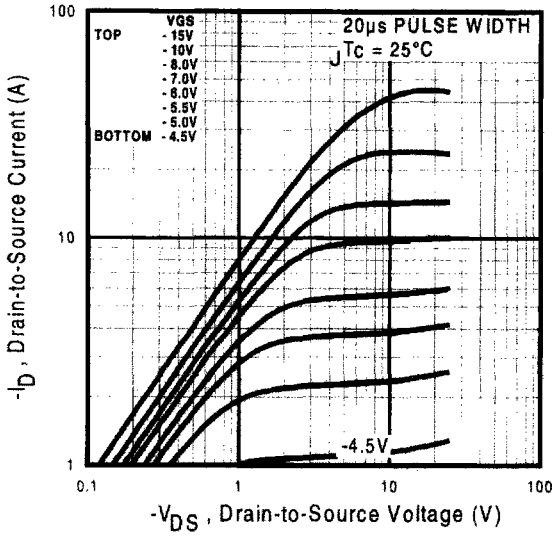


Fig 1. Typical Output Characteristics,

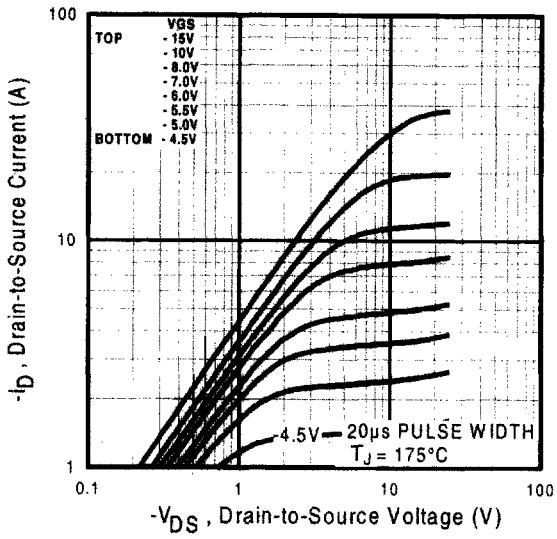


Fig 2. Typical Output Characteristics,

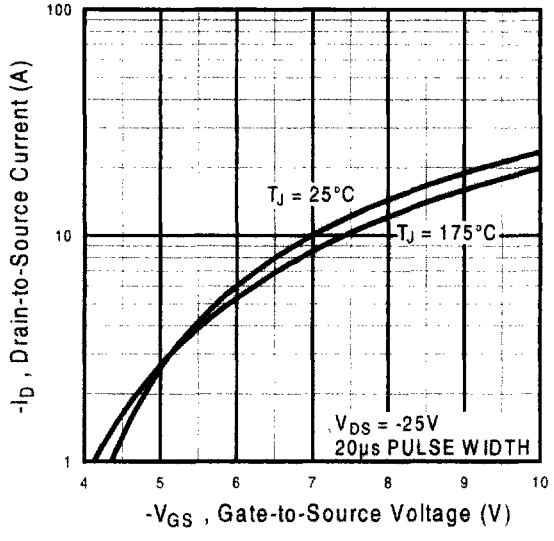


Fig 3. Typical Transfer Characteristics

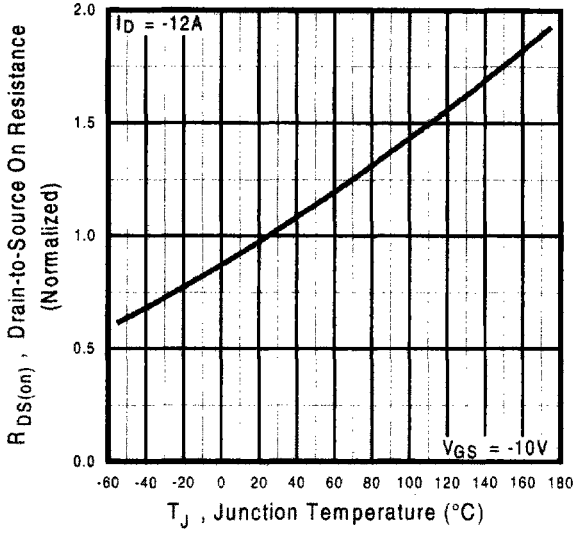


Fig 4. Normalized On-Resistance
Vs. Temperature

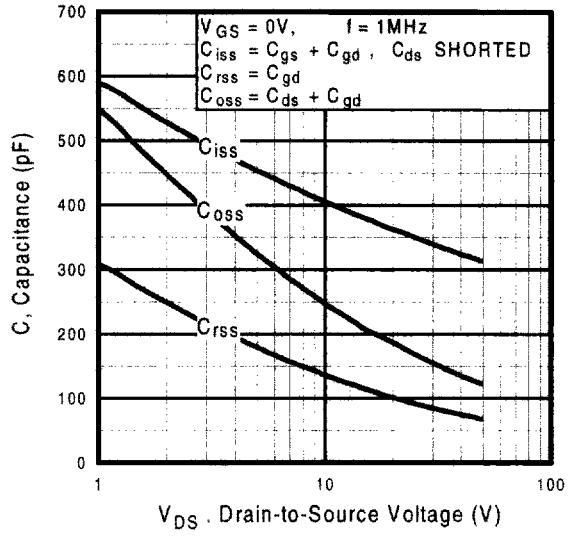


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

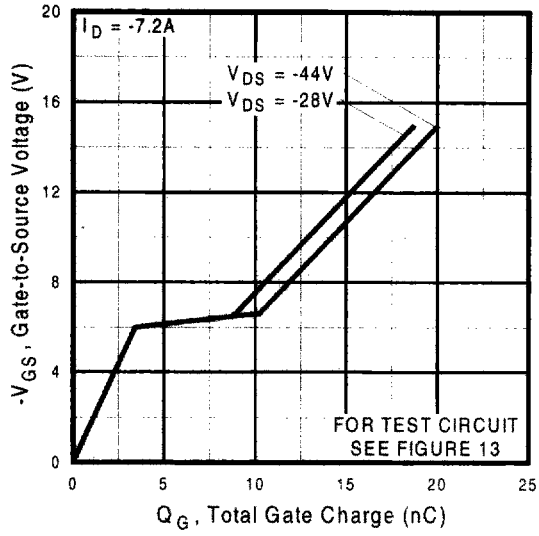


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

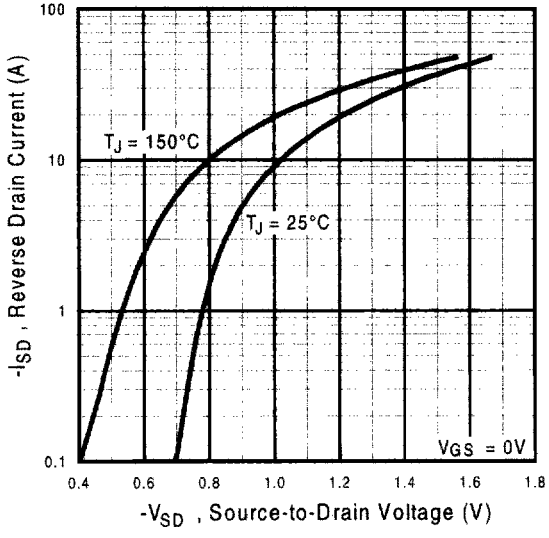


Fig 7. Typical Source-Drain Diode Forward Voltage

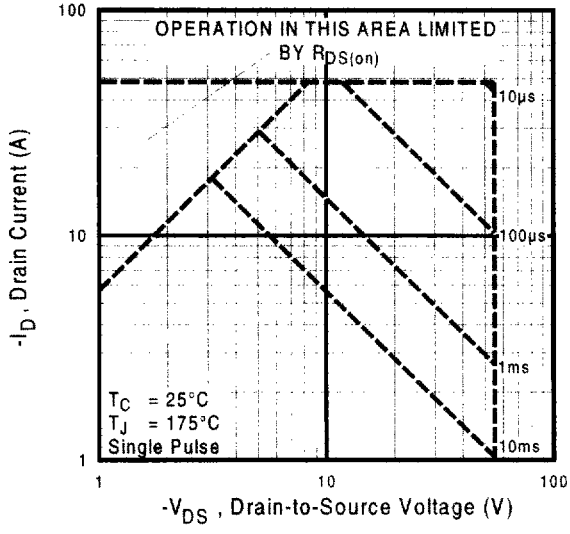


Fig 8. Maximum Safe Operating Area

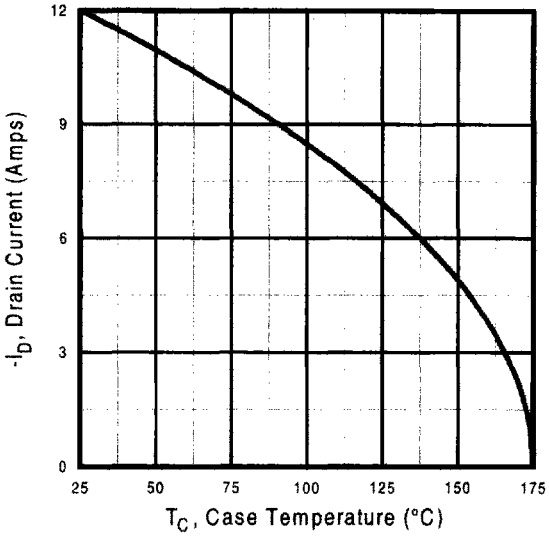


Fig 9. Maximum Drain Current Vs. Case Temperature

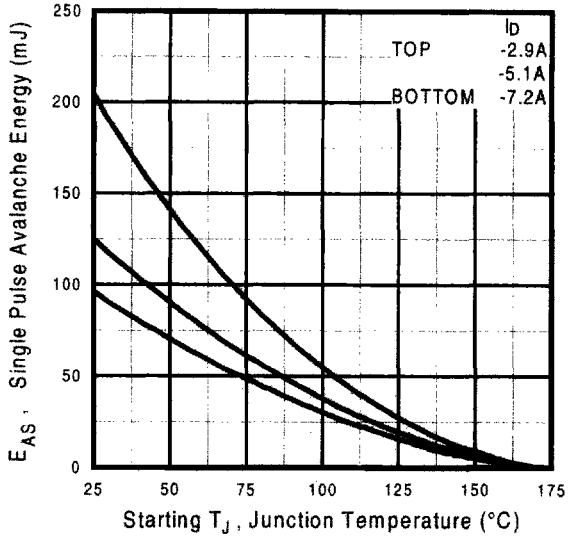


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

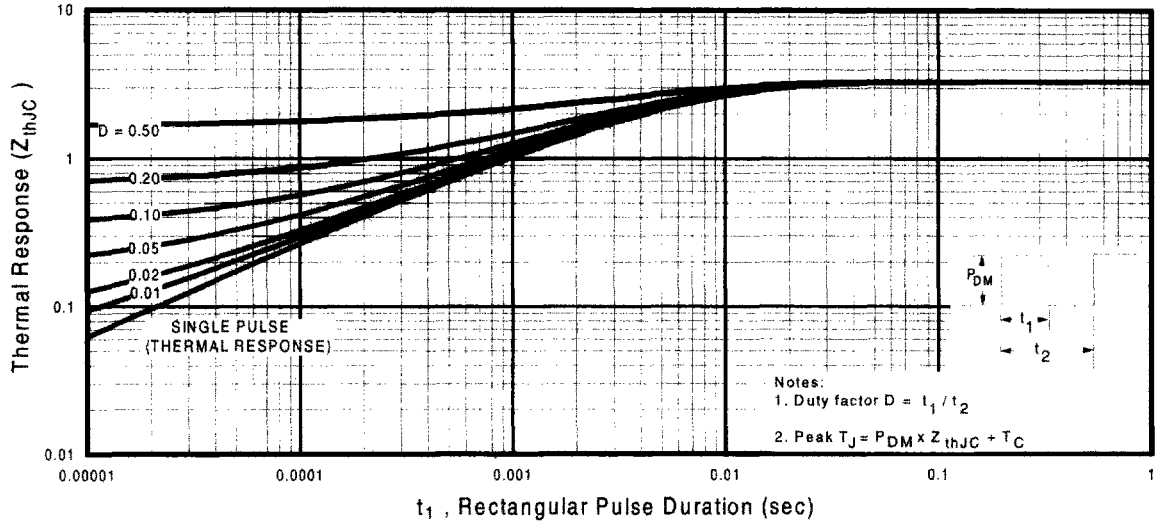


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

Mechanical drawings, Appendix A
Part marking information, Appendix B
Test Circuit diagrams, Appendix C